

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/831,262 GAMMERMAN ET AL.	
		Examiner Meltin Bell	Art Unit 2121	Page 1 of 1

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	B	US-5,846,189	12-1998	Pincus, Steven M.	600/301
	C	US-6,278,970	08-2001	Milner, Benjamin P	704/203
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**NON-PATENT DOCUMENTS**

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	V	Melluish et al; Comparing the Bayes and typicalness frameworks; Proceedings of ECML 01, Lecture Notes; 2001; pp 1-13
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	X	Kulkarni et al; On the existence of strongly consistent rules for estimation and classification; IEEE International Symposium on Information Theory Proceedings; 17-22 Sept. 1995; pp 255

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.